

Session DD:

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Network Measurements

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The topic of on-wafer characterization of microwave integrated circuits has been the focus of considerable interest in recent years. With the technology now becoming widely accepted, attention has shifted to improvements in accuracy, extended frequency range, higher measurement speed and more measurement system integration.

Improvements in measurement accuracy are being achieved through developments in network calibration algorithms and standards and an increasing emphasis on verification. Calibration methods based on “TRL” or its variants have become routine and high quality measurements are available through millimeter wave bands.

The papers in this session demonstrate the trends. Three of the papers are concerned with millimeter wave measurements, four use a TRL-type calibration method and four are concerned with accuracy improvement.

8:00 a.m.–9:30 a.m., Thursday, May 10, 1990
West Ballroom D